

---

---

**Space systems — Contamination and  
cleanliness control**

*Systèmes spatiaux — Contrôle de la contamination et de la propreté*



Reference number  
ISO 15388:2012(E)

© ISO 2012



**COPYRIGHT PROTECTED DOCUMENT**

© ISO 2012

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either ISO at the address below or ISO's member body in the country of the requester.

ISO copyright office  
Case postale 56 • CH-1211 Geneva 20  
Tel. + 41 22 749 01 11  
Fax + 41 22 749 09 47  
E-mail [copyright@iso.org](mailto:copyright@iso.org)  
Web [www.iso.org](http://www.iso.org)

Published in Switzerland

# Contents

Page

Foreword .....	iv
Introduction .....	v
<b>1 Scope .....</b>	<b>1</b>
<b>2 Normative references .....</b>	<b>1</b>
<b>3 Terms, definitions and abbreviated terms .....</b>	<b>1</b>
<b>3.1 Terms and definitions .....</b>	<b>1</b>
<b>3.2 Abbreviated terms .....</b>	<b>7</b>
<b>4 Management .....</b>	<b>8</b>
<b>4.1 Organization .....</b>	<b>8</b>
<b>4.2 Cleanliness requirement specification (CRS) .....</b>	<b>8</b>
<b>4.3 Contamination and cleanliness control plan (CCCP) .....</b>	<b>8</b>
<b>4.4 Interface control document (ICD) .....</b>	<b>9</b>
<b>4.5 Project reviews .....</b>	<b>9</b>
<b>5 Design activities .....</b>	<b>10</b>
<b>5.1 Identification of sensitive hardware .....</b>	<b>10</b>
<b>5.2 Nature of contaminants, their profile and their effects .....</b>	<b>10</b>
<b>5.3 Contamination prediction .....</b>	<b>10</b>
<b>5.4 Contamination budget .....</b>	<b>10</b>
<b>5.5 Cleanliness-oriented design .....</b>	<b>11</b>
<b>5.6 Selection of materials and processes .....</b>	<b>11</b>
<b>6 Biocontamination .....</b>	<b>12</b>
<b>6.1 General .....</b>	<b>12</b>
<b>6.2 Contamination of hardware by microorganisms .....</b>	<b>12</b>
<b>6.3 Sterile hardware .....</b>	<b>12</b>
<b>6.4 Habitable space systems .....</b>	<b>13</b>
<b>6.5 Planetary protection .....</b>	<b>13</b>
<b>6.6 Sample protection .....</b>	<b>13</b>
<b>7 Contamination and cleanliness control for ground operations .....</b>	<b>14</b>
<b>7.1 Training of personnel .....</b>	<b>14</b>
<b>7.2 Cleanroom selection and cleanliness control .....</b>	<b>14</b>
<b>7.3 Cleanroom garments .....</b>	<b>15</b>
<b>7.4 Ground support equipment (GSE) .....</b>	<b>15</b>
<b>7.5 Monitoring cleanliness of flight hardware and its near surroundings .....</b>	<b>15</b>
<b>7.6 Packaging, storage and transport .....</b>	<b>15</b>
<b>7.7 Cleaning of flight hardware .....</b>	<b>16</b>
<b>Annex A (informative) Material properties — Electronic databases .....</b>	<b>18</b>
<b>Bibliography .....</b>	<b>19</b>

## Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 2.

The main task of technical committees is to prepare International Standards. Draft International Standards adopted by the technical committees are circulated to the member bodies for voting. Publication as an International Standard requires approval by at least 75 % of the member bodies casting a vote.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights.

ISO 15388 was prepared by Technical Committee ISO/TC 20, *Aircraft and space vehicles*, Subcommittee SC 14, *Space systems and operations*.

This second edition cancels and replaces the first edition (ISO 15388:2004), which has been technically revised.

## Introduction

This International Standard addresses the preferred programme elements recommended for contamination and cleanliness control of space systems. This International Standard is written in general terms as a baseline for developing and implementing the control programme. It can be cited as a baseline within a statement of work and/or used for assuring proposal precision and contractor performance. The users are responsible for integrating the elements of this document appropriately to their programme needs.

The purpose of contamination and cleanliness control is to prevent the degradation of the performance of space systems due to particulate and molecular contamination (including biocontamination), and to ensure that the mission objectives are achieved.

ISO 9001:2015

# Space systems — Contamination and cleanliness control

## 1 Scope

This International Standard establishes general requirements for contamination and cleanliness control that are applicable, at all tiers of supply, to the development of space systems, including ground processing facilities, ground support equipment, launch vehicles, spacecraft, payloads, and ground processing and on-orbit operations. It also provides guidelines for the establishment of a contamination and cleanliness control programme.

## 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 14624-3, *Space systems — Safety and compatibility of materials — Part 3: Determination of offgassed products from materials and assembled articles*

ISO 14644-1, *Cleanrooms and associated controlled environments — Part 1: Classification of air cleanliness by particle concentration*

ISO 14698-1, *Cleanrooms and associated controlled environments — Biocontamination control — Part 1: General principles and methods*

ISO 14698-2, *Cleanrooms and associated controlled environments — Biocontamination control — Part 2: Evaluation and interpretation of biocontamination data*

ISO 14952 (all parts), *Space systems — Surface cleanliness of fluid systems*

ASTM E 595, *Standard Test Method for Total Mass Loss and Collected Volatile Condensable Materials from Outgassing in a Vacuum Environment*

ECSS-Q-ST-70-02C, *Space product assurance — Thermal vacuum outgassing test for the screening of space materials*

United Nations Treaty on Principles Governing the Activities of States in the Exploration and Use of Outer Space, including the Moon and Other Celestial Bodies, Article IX, 10 October 1967

## 3 Terms, definitions and abbreviated terms

### 3.1 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO 14952-1 and the following apply.

#### 3.1.1

##### **bakeout**

activity of increasing the temperature of hardware to accelerate its outgassing rates with the intent of reducing the content of molecular contaminants within the hardware

NOTE Bakeout is usually performed in a vacuum environment but may be done in a controlled atmosphere.

#### 3.1.2

##### **bioaerosol**

dispersed biological agents (e.g. viable particles, allergens, toxins or biologically active compounds of microbial origin) in a gaseous environment

**3.1.3**

**biocontamination**

contamination of materials, devices, individuals, surfaces, liquids, gases or air with viable particles

**3.1.4**

**classification**

(airborne particle concentrations) level (or process of specifying or determining the level) of airborne particulate cleanliness, expressed in terms of an ISO Class N, which represents maximum allowable concentrations for the particle size considered

NOTE 1 Concentrations are measured in particles per cubic metre.

NOTE 2 The concentrations are determined as specified in ISO 14644-1.

**3.1.5**

**clean bench**

table or bench-top working surface where a filtered airflow is concentrated across the bench top

NOTE These bench tops have an established classification of maximum allowable airborne contaminants.

**3.1.6**

**clean hood**

work area with a workbench, overhead dust deflector and sideboards, and a self-contained filtering unit for airflow to the work area

NOTE These hoods have an established classification of maximum allowable airborne contaminants.

**3.1.7**

**cleanliness level**

established maximum allowable amount of contamination in a given area or volume, or on a component

NOTE The term may also apply to the predicted or measured extent of contamination.

**3.1.8**

**cleanliness requirement specification**

**CRS**

document that defines and identifies the spacecraft items and the environmental areas which are sensitive to contamination, the acceptable contamination levels at beginning and end of life and the applicable contamination environment

**3.1.9**

**cleanroom**

room in which the concentration of airborne particles is controlled, and which is constructed and used in such a manner as to minimize the introduction, generation and retention of particles inside the room, and in which other relevant parameters such as temperature, humidity and pressure are controlled as necessary

**3.1.10**

**cleanroom garments**

clothing designed, manufactured and worn specifically to prevent contamination of hardware by personnel working in the cleanroom

NOTE Cleanroom garments include all items worn by personnel, such as coveralls, frocks, gloves, boots, finger cots and beard covers.

**3.1.11**

**clean zone**

dedicated space in which the concentration of airborne particles is controlled, and which is constructed and used in such a manner as to minimize the introduction, generation, and retention of particles inside the zone and in which other relevant parameters such as temperature, humidity and pressure are controlled as necessary

NOTE The clean zone may be open or enclosed and may or may not be located within a cleanroom.



**3.1.12****collected volatile condensable material****CVCM**

mass that outgasses from a material and subsequently condenses on a collector, expressed as a percentage of the initial specimen mass

**3.1.13****contaminant**

unwanted molecular or particulate matter that could affect or degrade the relevant performance or lifetime of the hardware to which it is attached

**3.1.14****contaminate**

introduce a contaminant

**3.1.15****contamination**

addition of contaminants to materials, fluids or surfaces

**3.1.16****contamination and cleanliness control programme**

organized effort to establish and achieve acceptable cleanliness and contamination levels during all phases of the space system project

**3.1.17****contamination analysis document**

report of the analyses and results that are used to determine cleanliness requirements and contamination profiles and budgets

**3.1.18****contamination and cleanliness control plan****CCCP**

document that describes how to implement a contamination and cleanliness control programme, as either an independent document or a part of the consolidated project plan

**3.1.19****contamination budget**

allowable levels of contamination of hardware at each phase of ground and flight operations

**3.1.20****contamination profile**

contamination-related conditions in each phase of ground and flight operations

NOTE 1 Conditions include airborne particulate cleanliness classes, pressure, humidity, temperature, number of personnel engaged in operations, cleaning activities, outlines of facilities and so on.

NOTE 2 The contamination profile is part of the CCCP.

**3.1.21****cross-contamination**

transfer of contaminants from one surface or component to another

NOTE Transfer can occur by migration along a surface, by physical contact, airborne as an aerosol, or as a gas or molecular matter.

**3.1.22****debris**

solid objects with their largest dimension greater than approximately 1 mm (1 000 µm) in size

**3.1.23**

**electrostatic discharge**

**ESD**

electrical breakdown of dielectric or gas or vacuum gaps, and also of surface interface of dissimilar materials, caused by differential charging of parts of dielectric materials and their interfaces

[ISO 11221:2011, 2.10]

**3.1.24**

**fibre**

flexible structure having a length-to-width ratio of 10 to 1 or greater

[ISO 14952-1:2003, 2.9]

**3.1.25**

**generally clean**

**GC**

free from manufacturing residue, dirt, oil, grease, processing debris, or other extraneous contamination based on visual examination

NOTE This level does not apply to hardware that is sensitive to contamination.

[ISO 14952-1:2003, 2.12]

**3.1.26**

**ground support equipment**

**GSE**

non-flight systems, equipment or devices necessary to support the operations of transporting, receiving, handling, assembly, inspection, test, checkout, servicing, launch and recovery of a space system at launch, landing or retrieval sites

[ISO 14625:2007, 3.1.5]

**3.1.27**

**ICD**

**interface control document**

specification that describes the characteristics that must be controlled at the boundaries between systems, subsystems and other elements

**3.1.28**

**microorganism**

microscopical individual constituted to carry out life functions

NOTE 1 Microorganisms include organisms such as bacteria, protozoa, yeasts, moulds, fungi, algae and organisms that depend upon other life forms for reproduction such as viruses and parasites.

NOTE 2 Multicellular organisms and agglomerations of microorganisms may be visible to the unaided eye.

**3.1.29**

**microscopical**

visible only under a microscope

**3.1.30**

**molecular contamination**

contamination due to deposition of molecules on surfaces or their presence in gases or liquids

**3.1.31**

**non-volatile residue**

**NVR**

quantity of soluble or suspended residual material and insoluble particulate matter remaining after temperature-controlled evaporation of a filtered, volatile liquid

NOTE Adapted from ISO 14952-1:2003, 2.17.

### 3.1.32 occupancy states of cleanrooms

#### 3.1.32.1 as-built

condition whereby the installation is complete with all services connected and functioning but with no equipment, materials, or personnel present

#### 3.1.32.2 at-rest

condition whereby the installation is complete with equipment installed, and operating in a manner agreed between the customer and supplier, but with no personnel present

#### 3.1.32.3 operational

condition whereby the installation is functioning in the specified manner, with the specified number of personnel present and working in the manner agreed upon

### 3.1.33 offgassing

evolution of gaseous products from a liquid or solid material into an atmosphere

NOTE This is a special definition of outgassing (see 3.1.34) for the application described in ISO 14624-3.

### 3.1.34 outgassing

evolution of gaseous species from a material, usually in a vacuum

NOTE Outgassing also occurs in higher-pressure environments.

### 3.1.35 particle

unit of solid or liquid matter with observable size

[ISO 14952-1:2003, 2.20]

NOTE See also 3.1.38, particle size.

### 3.1.36 particle concentration

⟨on surface⟩ number of particles per unit area

### 3.1.37 particle concentration

⟨by volume⟩ number of particles per unit volume of fluid

### 3.1.38 particle size

NOTE Various methods for defining size may be used and are dependent upon the measurement technique.

#### 3.1.38.1 particle size

⟨manual method⟩ apparent maximum linear dimension of a particle in the plane of observation as observed with instruments such as optical, electron, or atomic force microscopes

[ISO 14952-1:2003, 2.21.1]

**3.1.38.2**

**particle size**

(automatic method) equivalent diameter of a particle detected by automatic instrumentation

NOTE The equivalent diameter is the diameter of a reference sphere having known properties and producing the same response in the sensing instrument as the particle being measured.

[ISO 14952-1:2003, 2.21.2]

**3.1.39**

**particulate contamination**

contamination due to deposition of particles on surfaces or suspension of particles in fluids

**3.1.40**

**precision clean**

cleaning of hardware by approved engineering methods to meet quantitative cleanliness criteria

**3.1.41**

**responsible organization**

organization that is responsible for the contamination and cleanliness control programme and which is provided with the authority and resources needed to carry out the programme

**3.1.42**

**RML**

**recovered mass loss**

total mass loss of the specimen without the sorbed water:

$$\text{RML} = \text{TML} - \text{WVR}$$

where

TML is the total mass loss;

WVR is the water vapour regained

NOTE The quantity RML is introduced because water is not a critical contaminant for some space systems (see 5.6.3). In most cases, the value of WVR is similar to that of the mass of outgassed water. However, WVR is not exactly the same as the water mass effused from the specimen. Therefore, RML is not equal to the real value of the mass loss other than water.

**3.1.43**

**sensitive hardware**

hardware that can be degraded by contamination

**3.1.44**

**significant surface**

surface of an item or product that is required to meet established cleanliness level requirements

**3.1.45**

**spacecraft charging**

increase in electrostatic potential on spacecraft surfaces resulting from low-energy electron flux impinging on the surface

**3.1.46**

**sterility**

absence of viable microorganisms

NOTE Inactivated microbes can still represent an important form of biocontamination.

**3.1.47**

**sterilization**

act or process of killing all forms of microbial life on and in an object

NOTE Inactivated microbes might not be eliminated and can still represent an important form of biocontamination.

**3.1.48****supplier**

organization or person that provides a product

EXAMPLE Producer, distributor, retailer or vendor of a product, or provider of a service or information.

[ISO 9000:2005, 3.3.6]

**3.1.49****surface cleanliness**

level of contamination on a significant surface

**3.1.50****TML****total mass loss**

total mass of material outgassed from a test specimen that is maintained at a specified constant temperature and operating pressure for a specified time and measured within the test chamber

NOTE TML is expressed as a percentage of the initial specimen mass.

**3.1.51****viable particle**

isolated microorganisms or accumulated microorganisms (clumps) on a particle, capable of producing demonstrable growth

**3.1.52****visibly clean**

absence of surface contamination when examined using a specified light source and angle of incidence, viewing distance and angle, and normal or magnified vision

NOTE 1 This level requires precision-cleaning methods but a particle count may be optional.

NOTE 2 Fluorescence indicates possible contamination by, for example, a hydrocarbon.

NOTE 3 If recleaning fails to remove fluorescent indications, an investigation should be made to determine if the item material is naturally fluorescent or if the cleaning method is adequate.

[ISO 14952-1:2003, 2.35]

**3.1.53****WVR****water vapour regained**

mass of water vapour regained by a test specimen, after determination of TML and CVCM, on exposure to a specified relative humidity atmosphere (usually 50 % at 23 °C or 65 % at 20 °C) for 24 h

NOTE Some types of materials continue to absorb water for longer than 24 h. Repeated mass measurements after various time periods (e.g. 24 h, 48 h and 72 h) will give a better understanding of the material's water absorbency.

**3.2 Abbreviated terms**

AIT	assembly, integration and test
ASTM	American Society for Testing and Materials
BOL	beginning of (operational or mission) life
CCCP	contamination and cleanliness control plan
CRS	cleanliness requirement specification
CVCM	collected volatile condensable material
ECSS	European Cooperation for Space Standards

## ISO 15388:2012(E)

EOL	end of (operational or mission) life
ESA	European Space Agency
ESD	electrostatic discharge
GSE	ground support equipment
GSFC	Goddard Space Flight Center (NASA)
ICD	interface control document
IEST	Institute of Environmental Sciences and Technology (USA)
JAXA	Japan Aerospace Exploration Agency
NASA	National Aeronautics and Space Administration (USA)
NPD	NASA policy directive
NPG	NASA procedures and guidelines
NVR	non-volatile residue
RML	recovered mass loss
TML	total mass loss
WVR	water vapour regained

## 4 Management

### 4.1 Organization

The supplier shall establish a contamination and cleanliness control programme at the beginning of the project, for each level of configuration and item defined in the project. Performance requirements, defined by customer-supplier agreements, form the basis for cleanliness requirements.

### 4.2 Cleanliness requirement specification (CRS)

The supplier shall identify the hardware to be controlled, and specify the permissible cleanliness level in a quantitative manner. The hardware includes all items from component level to system level. The acceptable cleanliness levels of the hardware shall be specified at BOL and EOL, based on performance requirements and contamination analyses. The specification shall be established independently as a CRS or included in an overall project design specification. The cleanliness of hardware to be controlled at the boundary of systems, subsystems and other elements shall be stipulated in the ICD or its equivalent.

Cleanliness requirements that are more stringent than necessary to meet manufacturing and system performance requirements shall not be imposed at any level of assembly.

### 4.3 Contamination and cleanliness control plan (CCCP)

**4.3.1** Specifying cleanliness necessitates the establishment of a budget for particulate and molecular contamination for all phases of the project and a clear methodology of how the required cleanliness levels can be achieved.

**4.3.2** The supplier shall develop a contamination and cleanliness control plan that describes how to achieve and maintain the specified cleanliness level of the hardware during all the phases of the ground and flight operations. The plan may be an independent document or part of a consolidated project control plan.

**4.3.3** The range of the plan and the level of detail shall be determined by the responsible organization with respect to the criticality of the hardware against contamination. This may require other tasks in addition to those described in this document or may lead to a reduction in the applicable requirements.

**4.3.4** The CCCP shall

- a) contain a contamination budget for all phases of the ground and flight operations,
- b) provide methodology for achieving and maintaining the required cleanliness levels,
- c) define how to deal with situations that may result in cleanliness specifications not being achieved,

NOTE 1 Possible situations include failures of facilities and launch delays for a spacecraft.

NOTE 2 Corrective actions could include additional cleaning operations.

- d) define single-point failure modes that can affect cleanliness, including equipment failures and human errors,
- e) define the risk of cross-contamination between hardware elements,
- f) provide measurement and monitoring methods, procedures and requirements,
- g) define the sequence of cleanliness activities,
- h) define the roles and responsibilities of the organizations which will implement the requirements,
- i) provide descriptions of when and how the cleanliness activities are to be reviewed,
- j) provide information on how to implement design activities,
- k) provide information on how to train personnel and assess them, and
- l) provide references to procedures.

#### **4.4 Interface control document (ICD)**

**4.4.1** The cleanliness of hardware to be controlled at the interfaces of different systems, subsystems and other elements shall be stipulated in the ICD or its equivalent.

**4.4.2** The ICD may include the following types of information:

- a) limitations on particles, gases, vapours and debris crossing the interface;
- b) limitations on particles, gases, vapours and debris in the field of view of instruments and sensors;
- c) limitations on energy (ultraviolet and ionizing radiation, thermal radiation, radio frequency radiation, etc.) that will affect contaminant deposition and degrade performance.

#### **4.5 Project reviews**

The status of the contamination and cleanliness control programme shall be recorded and reported at the milestone project reviews where it shall be demonstrated that suitable activities are planned, are being implemented or have been successfully achieved.

## 5 Design activities

### 5.1 Identification of sensitive hardware

The supplier shall identify the sensitive hardware that may be degraded due to contamination during ground processing or flight and that shall be suitably protected. This hardware becomes the subject of detailed contamination and cleanliness control.

EXAMPLE Sensitive hardware includes optical detectors, optical assemblies and thermal control surfaces.

### 5.2 Nature of contaminants, their profile and their effects

#### 5.2.1 General

The supplier shall identify the following:

- a) the nature of the contaminants which may degrade the performance of sensitive hardware in any way, such as particulate, molecular or biocontaminants, during all phases of ground and flight operations;
- b) the effects of contaminants on the sensitive hardware, using experience gained with similar spacecraft or similar operations in early phases of the project and, later, using data gained in realistic tests.

#### 5.2.2 Typical contaminants

Typical contaminants are caused by factors such as outgassing (including re-emission of condensed contaminants, and return flux from collisions with the ambient atmosphere and spacecraft charging at high-Earth orbits); particles from materials, mechanisms or AIT facilities; grease from human handling, operation and AIT facilities; launch contaminants; leakage from pressurized units; microorganisms; ESD; exhaust products from thrusters; natural environments such as electron, proton and atomic oxygen fluxes; spacecraft charging; human waste dumps; and contamination from life support hardware.

#### 5.2.3 Contamination profile

The supplier shall initiate the contamination profile that shows contamination-related issues, such as temperature, pressure, humidity and natural environments, in each phase of the life cycle and shall maintain it throughout development.

#### 5.2.4 Effects of contamination on performance

The supplier shall develop a correlation between contamination levels and degradation in performance, and determine the allowable contamination limit for sensitive hardware. The cleanliness level requirements shall be estimated in the early phases, and become more detailed through performance analysis.

### 5.3 Contamination prediction

The supplier shall perform an analysis of contaminant transport and deposition for all phases of ground and flight operations. If the level of contamination exceeds the specifications, protective measures shall be implemented. The parameters necessary to perform the analysis could include view factors; the outgassing kinetics of relevant materials; the condensation kinetics and temperatures of significant surfaces; temperatures of outgassing sources; the reflectance on the surfaces; the scattering interactions with the neutral space environment; the electrodynamic interactions with ambient space plasma; surface interactions with space radiation, particularly with the incident ultraviolet radiation; etc.

### 5.4 Contamination budget

The supplier shall develop a contamination budget for both particulate and molecular species based on the contamination profile and design specification of hardware cleanliness. The contamination budget shall take into account the results of predictions, the probability of restoring cleanliness during ground and flight



operations, as well as exposure times and the use of protective covers. Methods to be used for cleaning and maintaining cleanliness throughout all phases of the project shall be considered. Contamination levels for BOL and EOL shall be included in the budget.

## 5.5 Cleanliness-oriented design

The supplier shall develop methods to maintain the cleanliness of sensitive hardware, to reduce its sensitivity to contamination and to ease cleaning, and shall describe the outline of the cleanliness-oriented design in the CCCP. Typical preventive measures include ensuring suitable location and orientation of sensitive hardware; minimizing the usage of outgassing materials; using venting holes, baffles and shields; using protective covers on the ground; controlling the temperature of outgassing hardware; designing cleaning processes; enclosing contamination sources; baking; processing human wastes; using molecular adsorbers, etc. The measures shall be chosen based on the cleanliness specification and the contamination budget.

The design of ground support equipment that is in the same room as, in close proximity to or in contact with, flight hardware shall also be similarly considered.

## 5.6 Selection of materials and processes

### 5.6.1 General

Materials and processes shall be selected to minimize contamination as well as to meet other functional requirements. The primary screening items for materials are outgassing, offgassing, particle generation, fungus growth and fragility.

### 5.6.2 Outgassing

The initial screening of materials shall be in accordance with ASTM E 595, ECSS-Q-ST-70-02C or a customer-recognized equivalent. Materials having TML of less than 1,0 %, RML of less than 1,0 % and CVCM of less than 0,1 % are generally considered as low-outgassing materials. The figures do not represent the acceptance criteria. Materials should be selected considering also temperature, mass and surface area in use.

A material is considered as a possible contamination source under the following conditions. In these cases, even a low-outgassing material can cause contamination problems.

- a) The material is used nearby, or in direct view of, the contamination-sensitive surfaces.
- b) The material is used nearby, or in direct view of, the cryogenic surfaces.
- c) The material is used in large amounts.
- d) The material is expected to be at a higher temperature than other surfaces.

A material is considered to pose less of a risk of contaminating other surfaces under the following conditions. In these cases, materials not considered as low-outgassing material can be applied with no or small contamination impact.

- The material is used far from, or is not in direct view of, the contamination-sensitive surfaces.
- The material is used far from, or is not in direct view of, the cryogenic surfaces.
- The material is used in small amounts.
- The material is expected to be at a lower temperature than other surfaces.

The requirements for the use of TML and RML depend on the performance requirements for the space system and specific uses of materials in the system (see 5.6.3).

Materials that pass the standard screening tests may nevertheless cause degradation of sensitive hardware and may require further characterization. The customer and supplier shall establish materials selection guidelines, with requirements that are more stringent, using other test methods, if justified by mission and performance requirements.

Material selection adequacy is verified by contamination prediction (see 5.3). Even materials which do not meet the materials selection guidelines may be used as long as the predicted level of contamination meets the contamination budget (see 5.3, 5.4).

NOTE Long-term outgassing estimation using ASTM E 1559 (see Reference [29]) and other, similar test methods may be applicable for establishing guidelines for the selection of materials.

### 5.6.3 Absorbed water vapour

Some materials contain large quantities of absorbed water that contribute to the TML. If the outgassing of water vapour is not critical to the application, the outgassed water may be subtracted from the TML to provide an RML to meet the requirements. The adjusted mass loss value is given by the RML:

$$\text{RML} = \text{TML} - \text{WVR}$$

### 5.6.4 Offgassing

Materials shall be screened, in accordance with ISO 14624-3, for their offgassing characteristics, carrying out a toxicological assessment of the risks to personnel when the materials are used in habitable areas during flight.

### 5.6.5 Quality control

Suitable quality control processes to verify the performance of materials shall be maintained. Processes and compositions of commercial materials might not be controlled sufficiently to meet the requirements of space systems. The specification of quality control processes shall be determined on a case-by-case basis.

ASTM E 595 or ECSS-Q-70-02C may be used as a quality control test for the outgassing characteristics of materials.

## 6 Biocontamination

### 6.1 General

The organisms that cause biocontamination are fungi, yeast, viruses and bacteria. They are contaminants by virtue of their biomass and also generate contaminants by virtue of their biological processes, thriving both on the ground and in flight. They are introduced on the ground during manufacturing, integrating and testing, transporting and operating processes. Human waste and metabolic byproducts accelerate the growth of microorganisms associated with water or nutrients. Hardware cleanliness can include requirements for viable organisms as well as dead organisms, chemical and particulate byproducts, and metabolic products from the organisms.

### 6.2 Contamination of hardware by microorganisms

6.2.1 Microorganisms produce substances that result from their metabolic and/or biological processes. These materials can cause contamination or corrosion.

6.2.2 A preventive measure is to eliminate or reduce moisture and nutrients. The prevention of the propagation of microorganisms, especially in rooms with recirculating-air systems, is difficult. Effective countermeasures include installing high-performance filters and implementing effective cleaning processes. Designing hardware so that it is easily cleanable is also an important countermeasure.

### 6.3 Sterile hardware

6.3.1 Sterility requirements may be imposed on hardware for use in habitable systems, biological experiments and interplanetary missions. These requirements may be in addition to other contamination control requirements imposed on the system.

**6.3.2** Sterile processing procedures include, but are not limited to, eliminating contact with contaminated objects, with bioaerosols in air and purge gases, and with personnel.

**6.3.3** Ground-handling processes shall be designed to fulfil the sterility requirements on hardware. This includes keeping the hardware in sterile environments, such as sterile packaging, sterile isolators and sterile rooms, in accordance with the procedures described in ISO 14698-1. The CCCP shall include, or reference, the procedures required to meet hardware requirements.

**6.3.4** Ground operations shall be monitored to verify that hardware cleanliness and environments meet the requirements. Evaluation and interpretation of biocontamination data shall be in accordance with ISO 14698-2.

**6.3.5** Personnel shall be provided with proper garments, as required, to prevent exposure to hazardous contaminants and to protect hardware from contamination.

## **6.4 Habitable space systems**

### **6.4.1 Habitable spacecraft**

Specific measures shall be taken to protect onboard personnel from harmful contaminants, including biocontaminants and toxic materials. The measures shall include the control of outgassing (offgassing) from materials and hardware and control of the flammability of materials. Objectionable odours should also be controlled to maintain a comfortable environment within the habitable spacecraft if this is required for the particular space programme. Special atmospheres, such as pure oxygen, shall also be considered in defining the requirements.

### **6.4.2 Offgassing**

Materials used in habitable locations of spacecraft shall be screened for offgassing in accordance with ISO 14624-3.

## **6.5 Planetary protection**

**6.5.1** Planetary protection activities shall be included in the CCCP, in accordance with Article IX of the United Nations Treaty on Principles Governing the Activities of States in the Exploration and Use of Outer Space, Including the Moon and Other Celestial Bodies, which contains the following requirement in particular: "States Parties to the Treaty shall pursue studies of outer space, including the Moon and other celestial bodies, and conduct exploration of them so as to avoid their harmful contamination and also adverse changes in the environment of the Earth resulting from the introduction of extraterrestrial matter and, where necessary, shall adopt appropriate measures for this purpose."

**6.5.2** Protection of other planets requires limits on the quantities of viable organisms that may be transported to a planet that could have life forms currently, or might have had them in the past. The level of protection required depends upon scientific judgement of the probability of life on the planet.

**6.5.3** Protection of the Earth requires procedures that prevent possibly harmful organisms from other planets damaging the inhabitants and the environment of the Earth when vehicles and samples are transported back to the Earth.

## **6.6 Sample protection**

Biological samples from scientific studies and routine monitoring shall be protected from contamination as necessary to meet system performance requirements. The protection methods shall be included in the CCCP.

## 7 Contamination and cleanliness control for ground operations

### 7.1 Training of personnel

Personnel shall be trained in accordance with the CCCP and shall comply with it, according to their assigned tasks. Additional information relating to personnel in cleanrooms can be found in ISO 14644-5:2004, 4.3 and Annex C.

### 7.2 Cleanroom selection and cleanliness control

#### 7.2.1 General

**7.2.1.1** The supplier shall select, based on the contamination budget (see 5.4), suitable environments for the manufacture, assembly, transportation, integration and testing of hardware. This includes launch site processing.

**7.2.1.2** Cleanroom selection shall be based on hardware cleanliness requirements, required operating procedures and exposure times.

**7.2.1.3** Allowable airborne particle concentrations shall be specified as a class of air for the operational occupancy state, in accordance with ISO 14644-1.

**7.2.1.4** Procedures for operational and at-rest conditions shall be specified to the extent necessary to meet hardware cleanliness requirements.

**7.2.1.5** Special clean zones may be established to meet special hardware cleanliness requirements in a local area.

**7.2.1.6** Operational monitoring of airborne and surface contaminants shall be specified to the extent required to meet project performance requirements and risk/cost benefits.

**7.2.1.7** Materials, parts, hardware and test equipment that are authorized to be taken into cleanrooms shall be compatible with the cleanliness requirements of the area. An approved list of materials for use in cleanroom areas is recommended. The cognizant contamination control or systems engineer shall approve materials for use in cleanrooms.

#### 7.2.2 Failure of facilities

**7.2.2.1** Failures of facilities, such as electrical power and cooling water, and equipment breakdown shall be considered in the CCCP and in relevant operating procedures that are defined so as to prevent damage to flight hardware.

**7.2.2.2** Single-point failure mechanisms, including human error, shall be analysed and measures shall be taken to avoid them, with special consideration given to risk/cost benefits.

#### 7.2.3 Facility operating procedures

Facility operating procedures include overall cleaning and control of the cleanroom, monitoring of facility cleanliness and maintaining facilities. When flight hardware is present, cleaning of the cleanroom shall be limited to the extent necessary to meet hardware cleanliness requirements.

#### 7.2.4 Additional information

**7.2.4.1** Additional information on the design, construction and start-up of cleanrooms can be found in ISO 14644-4.

**7.2.4.2** Additional information on the operation of cleanrooms can be found in ISO 14644-5.

## 7.3 Cleanroom garments

### 7.3.1 General

One purpose of a cleanroom garment is to prevent contaminants generated by people from getting to the product. For some applications, the garment is also used to protect personnel from hazardous materials.

### 7.3.2 Considerations for garment selection

**7.3.2.1** Garments shall be selected based on hardware cleanliness requirements, the type of airflow in the cleanroom and the location of the personnel relative to the hardware. The usual garment choices for aerospace use include a full coverall with a hood and shoe coverings or a frock and partial head cover with some type of shoe cover.

**7.3.2.2** The garment shall have good ESD protection, high permeability to air and water vapour, low particle transmission capacity, low particle generation capacity, good cleanability and good wear properties, including resistance to laundering and dry cleaning.

**7.3.2.3** For garment selection, one should note that a frock does not retain the particles generated by the wearer of the garment because the bottom is open. Studies have shown that airborne-particle concentrations increase when frocks are worn as compared to coveralls. The open bottom allows large particles and debris to fall out. These will not become airborne but will deposit on the cleanroom floor or on product surfaces near the wearer. Frockes are not recommended when personnel are working above hardware or when product cleanliness levels are stringent. Frockes are suitable for the processing of hardware in clean benches where coveralls are not needed.

### 7.3.3 Additional information

Additional information on the selection and use of cleanroom garments can be found in ISO 14644-5:2004, 4.2 and Annex B.

## 7.4 Ground support equipment (GSE)

For the selection and operation of ground support equipment in the same room as, or near, flight hardware, the cleanliness requirements of the flight hardware, and contamination sources such as outgassing and lubricants, shall be taken into consideration. Particle-generating materials or fragile surfaces shall be sealed or covered as well as possible.

Equipment-cooling fans can generate a flow of molecular or particulate matter. The exclusion of such fans or the re-direction of their airflow away from flight hardware shall be considered.

## 7.5 Monitoring cleanliness of flight hardware and its near surroundings

Contamination shall be monitored to the predetermined levels and time intervals as per the procedures defined in the CCCP. Monitoring equipment shall be located at suitable places and under specified conditions.

The cleanliness shall be monitored and recorded as per test plans and operating procedures, as required. Monitoring may include the following: concentrations of airborne particulate and molecular contaminants; deposition of particulate and molecular contaminants; temperature; relative humidity and room pressure.

A method for monitoring airborne-particle concentrations in cleanrooms is given in ISO 14644-2. Additional measurement methods can be found in ISO 14644-3.

## 7.6 Packaging, storage and transport

### 7.6.1 Packaging

Packaging shall be used to protect hardware during storage and transport. Packaging materials shall not increase the contamination of the hardware or contain volatile or transferable contaminants.

## 7.6.2 Storage

Storage areas shall provide adequate protection to the package and the product for the intended storage period.

## 7.6.3 Transport

Containers shall be used during transport. The materials from which the containers are made shall be selected considering volatile and transferable contaminants, the method of transport and the transport environments.

## 7.7 Cleaning of flight hardware

### 7.7.1 General

The supplier shall meet the cleanliness requirements for the hardware and the contamination budget as stated in the CCCP. For fluids, cleanliness levels shall be determined in accordance with ISO 14952, particularly ISO 14952-3. Cleaning of flight hardware is critical for the stages of assembly, integration, testing, transportation and launch operations. The supplier shall select the cleaning procedures, methods, equipment, frequency and agents that are most suitable for each stage of processing, according to the species of contaminant and compatibility with the hardware.

NOTE IEST-STD-CC1246 (see Reference [16]) can be applicable for defining hardware cleanliness.

### 7.7.2 Cleaning procedures

The scope of the cleaning processes shall be outlined in the CCCP, quoting independent existing documents if necessary. The required skills, cares, specification of cloths, cleaning agents, aids and equipment, directives and stages, etc., including their cleanliness levels, shall be described and qualified.

Processes giving a “generally clean” level of cleanliness (see 3.1.25) may be used before further cleaning using a precision-cleaning process, or without further cleaning if quantitative cleanliness levels are not required. The cleanliness level “generally clean” shall not be designated for hardware that is sensitive to contamination.

“Visibly clean” inspections shall be performed in accordance with approved procedures and can provide a quantitative evaluation of cleanliness levels.

### 7.7.3 Bakeout

Bakeout of flight hardware can be an effective measure to reduce outgassing rates and potential contaminants. Bakeout may be conducted in a vacuum or in a flowing, controlled gas environment, such as clean, dry, gaseous nitrogen. Bakeout procedures are not all equivalent with respect to results. Engineering analysis and judgement shall be used to select the bakeout procedure that is cost-effective and that meets system performance requirements.

Bakeout may be conducted at any level of hardware assembly, from component to system, depending upon analyses and system performance requirements. Special care should be taken to prevent cross-contamination when the articles under bakeout have sensitive hardware.

Bakeout procedures shall be included or referenced in the CCCP, specifying conditions such as the level of vacuum or gas and gas flow rate, the temperature, the duration and monitoring methods.

### 7.7.4 Contaminant source containment

It may be possible to reduce contamination by using coatings, anticreep barriers and shields.

### 7.7.5 Purging

Clean gases can be used to purge flight hardware, in order to prevent contaminants from entering critical components. Clean nitrogen, helium, argon and air have been used. Safety shall be taken into account; ISO 15859-3, ISO 15859-4 and ISO 15859-9 may be used as applicable. Additional filtration at the point of use

may be required to meet cleanliness requirements. Purge-gas requirements, purge times and allowable non-purge times shall be included in the CCCP as applicable.

## Annex A (informative)

### Material properties — Electronic databases

This annex includes a number of online resources that provide relevant information on the properties of materials used for space systems:

- NASA Goddard Space Flight Center (GSFC) outgassing data: <http://outgassing.nasa.gov/>
- NASA Materials and Processes Technical Information System (MAPTIS): <http://maptis.nasa.gov>
- ESA outgassing data: [http://esmat.esa.int/Services/outgassing\\_data/outgassing\\_data.html](http://esmat.esa.int/Services/outgassing_data/outgassing_data.html)
- JAXA Materials Database: [http://matdb1n.tksc.jaxa.jp/main\\_e.html](http://matdb1n.tksc.jaxa.jp/main_e.html)



## Bibliography

### International Standards

- [1] ISO 9000:2005, *Quality management systems — Fundamentals and vocabulary*
- [2] ISO 11221:2011, *Space systems — Space solar panels — Spacecraft charging induced electrostatic discharge test methods*
- [3] ISO 14644-2, *Cleanrooms and associated controlled environments — Part 2: Specifications for monitoring and periodic testing to prove continued compliance with ISO 14644-1*
- [4] ISO 14644-3, *Cleanrooms and associated controlled environments — Part 3: Test methods*
- [5] ISO 14644-4, *Cleanrooms and associated controlled environments — Part 4: Design, construction and start-up*
- [6] ISO 14644-5:2004, *Cleanrooms and associated controlled environments — Part 5: Operations*
- [7] ISO 14644-6, *Cleanrooms and associated controlled environments — Part 6: Vocabulary*
- [8] ISO 14644-7, *Cleanrooms and associated controlled environments — Part 7: Separative devices (clean air hoods, gloveboxes, isolators and mini-environments)*
- [9] ISO 14644-8, *Cleanrooms and associated controlled environments — Part 8: Classification of airborne molecular contamination*
- [10] ISO 15859-3, *Space systems — Fluid characteristics, sampling and test methods — Part 3: Nitrogen*
- [11] ISO 15859-4, *Space systems — Fluid characteristics, sampling and test methods — Part 4: Helium*
- [12] ISO 15859-9, *Space systems — Fluid characteristics, sampling and test methods — Part 9: Argon*

### ECSS documents

- [13] ECSS-Q-ST- 70-01C, *Space product assurance — Cleanliness and contamination control*

### NASA documents

- [14] NPD 8020.7E, *Biological Contamination Control for Outbound and Inbound Planetary Spacecraft*
- [15] NPG 8020.12B, *Planetary Protection Provisions For Robotic Extraterrestrial Missions*

### IEST documents

- [16] IEST-STD-CC1246, *Product Cleanliness Levels and Contamination Control Program*
- [17] IEST-RP-CC003, *Garment System Considerations for Cleanrooms and Other Controlled Environments*
- [18] IEST-RP-CC003.2 (Supplement), *Garment Sterilization Considerations for Microbiologically Controlled Environments*
- [19] IEST-RP-CC006, *Testing Cleanrooms*
- [20] IEST-RP-CC012, *Considerations in Cleanroom Design*
- [21] IEST-RP-CC016, *The Rate of Deposition of Nonvolatile Residue in Cleanrooms*
- [22] IEST-RP-CC022, *Electrostatic Charge in Cleanrooms and Other Controlled Environments*
- [23] IEST-RP-CC023, *Microorganisms in Cleanrooms*
- [24] IEST-RP-CC026, *Cleanroom Operations*

**ASTM documents**

- [25] ASTM E 1216, *Standard Practice for Sampling for Particulate Contamination by Tape Lift*
- [26] ASTM E 1235, *Standard Test Method for Gravimetric Determination of Nonvolatile Residue (NVR) in Environmentally Controlled Areas for Spacecraft*
- [27] ASTM E 1548, *Standard Practice for Preparation of Aerospace Contamination Control Plans*
- [28] ASTM E 1549, *Standard Specification for ESD Controlled Garments Required in Cleanrooms and Controlled Environments for Spacecraft for Non Hazardous and Hazardous Operations*
- [29] ASTM E 1559, *Standard Test Method for Contamination Outgassing Characteristics of Spacecraft Materials*
- [30] ASTM E 1560, *Standard Test Method for Gravimetric Determination of Nonvolatile Residue from Cleanroom Wipers*
- [31] ASTM E 1731, *Standard Test Method for Gravimetric Determination of Nonvolatile Residue from Cleanroom Gloves*
- [32] ASTM E 1997, *Standard Practice for the Selection of Spacecraft Materials*
- [33] ASTM E 2042, *Standard Practice for Cleaning and Maintaining Controlled Areas and Clean Rooms*
- [34] ASTM E 2088, *Standard Practice for Selecting, Preparing, Exposing, and Analyzing Witness Surfaces for Measuring Particle Deposition in Cleanrooms and Associated Controlled Environments*
- [35] ASTM E 2090, *Standard Test Method for Size Differentiated Counting of Particles and Fibers Released from Cleanroom Wipers Using Optical and Scanning Electron Microscopy*
- [36] ASTM F 50, *Standard Practice for Continuous Sizing and Counting of Airborne Particles in Dust Controlled Areas and Clean Rooms Using Instruments Capable of Detecting Single Sub Micrometre and Larger Particles*
- [37] ASTM F 51, *Standard Test Method for Sizing and Counting Particulate Contaminant In and On Clean Room Garments*

1  
2  
3  
4  
5  
6  
7  
8  
9  
10  
11  
12  
13  
14  
15  
16  
17  
18  
19  
20  
21  
22  
23  
24  
25  
26  
27  
28  
29  
30  
31  
32  
33  
34  
35  
36  
37  
38  
39  
40  
41  
42  
43  
44  
45  
46  
47  
48  
49  
50  
51  
52  
53  
54  
55  
56  
57  
58  
59  
60  
61  
62  
63  
64  
65  
66  
67  
68  
69  
70  
71  
72  
73  
74  
75  
76  
77  
78  
79  
80  
81  
82  
83  
84  
85  
86  
87  
88  
89  
90  
91  
92  
93  
94  
95  
96  
97  
98  
99  
100

---

---

**ICS 49.140**

Price based on 20 pages